

Search Notes



Application/Control No.

10/808,818

Examiner

Emmanuel S. Luk

Applicant(s)/Patent under Reexamination

JEON ET AL.

Art Unit

1722

SEARCHED

Class	Subclass	Date	Examiner
425	190	1/7/2006	EL
425	191	1/7/2006	EL
425	208	1/7/2006	EL
425	209	1/7/2006	EL
425	558	1/7/2006	EL
366	76.3	1/7/2006	EL
366	79	1/7/2006	EL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see EAST text search		1/7/2006	EL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST text search	1/7/2006	EL